

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/785,417	PARK ET AL.	
Examiner		William H. Rodríguez	Art Unit	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
*	B	US-3,697,197 A	10-1972	Berglund et al.	417/360
*	C	US-4,566,865 A	01-1986	Nishitsuji et al.	417/363
*	D	US-4,808,085 A	02-1989	Nishitsuji, Kazuichi	417/363
*	E	US-6,287,092 B1	09-2001	Calciolari et al.	417/415
*	F	US-D455,641 S	04-2002	Trifilio, Christian R.	D8/354
*	G	US-2005/0142007 A1	06-2005	Lee et al.	417/415
*	H	US-2005/0142008 A1	06-2005	Jung et al.	417/417
*	I	US-2005/0214140 A1	09-2005	Lee et al.	417/416
*	J	US-2005/0201875 A1	09-2005	Park, Seung Il	417/417
*	K	US-2006/0018771 A1	01-2006	Song et al.	417/416
*	L	US-2006/0057000 A1	03-2006	Hyeon, Seong-Yeol	417/415
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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